

FDMS3622S PowerTrench[®] Power Stage 25V Asymmetric Dual N-Channel MOSFET

Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 5.0 m Ω at V_{GS} = 10 V, I_D = 17.5 A
- Max $r_{DS(on)}$ = 5.7 m Ω at V_{GS} = 4.5 V, I_D = 16 A

Q2: N-Channel

- Max $r_{DS(on)}$ = 1.4 m Ω at V_{GS} = 10 V, I_D = 34 A
- Max r_{DS(on)} = 1.6 mΩ at V_{GS} = 4.5 V, I_D = 32 A
- Low inductance packaging shortens rise/fall times, resulting in lower switching losses
- MOSFET integration enables optimum layout for lower circuit inductance and reduced switch node ringing
- RoHS Compliant

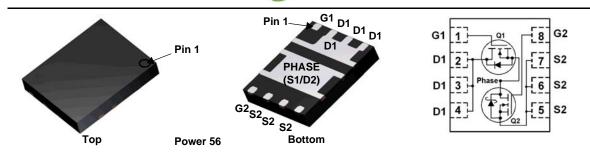


General Description

This device includes two specialized N-Channel MOSFETs in a dual PQFN package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous SyncFET (Q2) have been designed to provide optimal power efficiency.

Applications

- Computing
- Communications
- General Purpose Point of Load
- Notebook VCORE



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter			Q2	Units
V _{DS}	Drain to Source Voltage		25	25	V
V _{GS}	Gate to Source Voltage	(Note 4)	±12	±12	V
	Drain Current -Continuous (Package limited)	T _C = 25 °C	30	70	
ID	-Continuous	T _A = 25 °C	17.5 ^{1a}	34 ^{1b}	А
	-Pulsed		70	140	_
E _{AS}	Single Pulse Avalanche Energy	29	145	mJ	
P _D	Power Dissipation for Single Operation		2.2 ^{1a}	2.5 ^{1b}	w
	Power Dissipation for Single Operation $T_A = 25 \text{ °C}$		1.0 ^{1c}	1.0 ^{1d}	vv
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to	+150	°C

Thermal Characteristics

$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	57 ^{1a}	50 ^{1b}	
R_{\thetaJA}	Thermal Resistance, Junction to Ambient	125 ^{1c}	120 ^{1d}	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.0	1.9	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
08OD 09OD	FDMS3622S	Power 56	13 "	12 mm	3000 units

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Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Off Chara	cteristics						
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0 \ V$ $I_D = 1 \ m A, \ V_{GS} = 0 \ V$	Q1 Q2	25 25			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C $I_D = 10 \ \text{mA}$, referenced to 25 °C	Q1 Q2		12 24		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 20 V, V_{GS} = 0 V$	Q1 Q2			1 500	μΑ μΑ
I _{GSS}	Gate to Source Leakage Current	V_{GS} = 12 V/-8 V, V_{DS} = 0 V	Q1 Q2			±100 ±100	nA nA
On Chara	cteristics						
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, \ I_D = 250 \ \mu A$ $V_{GS} = V_{DS}, \ I_D = 1 \ m A$	Q1 Q2	0.8 1.1	1.2 1.4	2.0 2.2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C $I_D = 10 \ m$ A, referenced to 25 °C	Q1 Q2		-4 -4		mV/°C
		$ \begin{array}{l} V_{GS} = 10 \text{ V}, \ \text{I}_{D} = 17.5 \text{ A} \\ V_{GS} = 4.5 \text{ V}, \ \text{I}_{D} = 16 \text{ A} \\ V_{GS} = 10 \text{ V}, \text{I}_{D} = 17.5 \text{ A}, \text{T}_{J} = 125 \ ^{\circ}\text{C} \end{array} $	Q1		3.8 4.4 5.4	5.0 5.7 7.0	– mΩ
r _{DS(on)}	Drain to Source On Resistance	V _{GS} = 10 V, I _D = 34 A V _{GS} = 4.5 V, I _D = 32 A V _{GS} = 10 V, I _D =34 A ,T _J =125 °C	Q2		1.1 1.3 1.5	1.4 1.6 2.0	
9 _{FS}	Forward Transconductance	$V_{DS} = 5 V, I_D = 17.5 A$ $V_{DS} = 5 V, I_D = 34 A$	Q1 Q2		100 272		S
Dynamic	Characteristics						
C _{iss}	Input Capacitance	Q1: V _{DS} = 13 V, V _{GS} = 0 V, f = 1 MHZ	Q1 Q2		1570 5565		pF
C _{oss}	Output Capacitance	Q2:	Q1 Q2		448 1405		pF
C _{rss}	Reverse Transfer Capacitance	V _{DS} = 13 V, V _{GS} = 0 V, f = 1 MHZ	Q1 Q2		61 182		pF
R _g	Gate Resistance		Q1 Q2		0.4 0.8		Ω
Switching	g Characteristics						
t _{d(on)}	Turn-On Delay Time		Q1 Q2		7 14		ns
t _r	Rise Time	Q1: V _{DD} = 13 V, I _D = 17.5 A, R _{GEN} = 6 Ω	Q1 Q2		2 7		ns
t _{d(off)}	Turn-Off Delay Time	 Q2: V _{DD} = 13 V, I _D = 34 A, R _{GEN} = 6 Ω			23 48		ns
t _f	Fall Time		Q1 Q2		2 6		ns
Qg	Total Gate Charge	$V_{GS} = 0$ V to 10 V Q1	Q1 Q2		26 86		nC
Qg	Total Gate Charge	$V_{GS} = 0 V \text{ to } 4.5 V V_{DD} = 13 V,$ $I_{D} = 17.5 A$	Q1 Q2		12 40		nC
			-			1	1

Gate to Source Gate Charge

Gate to Drain "Miller" Charge

 Q_{gs}

 Q_{gd}

nC

nC

Q2

 $V_{DD} = 13 V,$ $I_{D} = 34 A$ Q1

Q2

Q1

Q2

3.3

12

2.7

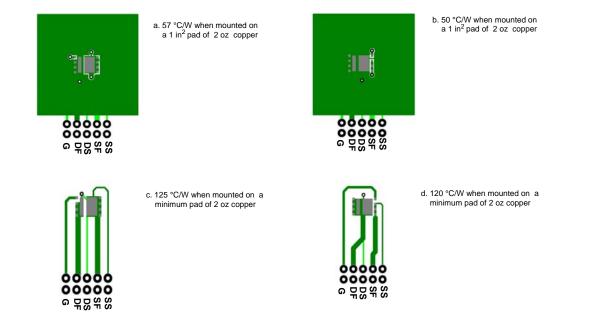
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Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Drain-Sou	urce Diode Characteristics						
V	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_S = 17.5 A$ (Note 2)	Q1		0.8	1.2	V
V _{SD} Source to Drain Diode For	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_S = 17.5 A$ (Note 2) $V_{GS} = 0 V, I_S = 34 A$ (Note 2)	Q2		0.8	1.2	v
		Q1	Q1		23		
ι _{rr}	Reverse Recovery Time	I _F = 17.5 A, di/dt = 100 A/μs	Q2		35		ns
0	David David Olympic	Q2	Q1		9		nC
Q _{rr}	Reverse Recovery Charge	I _F = 34 A, di/dt = 300 A/μs	Q2		43	n	

Notes

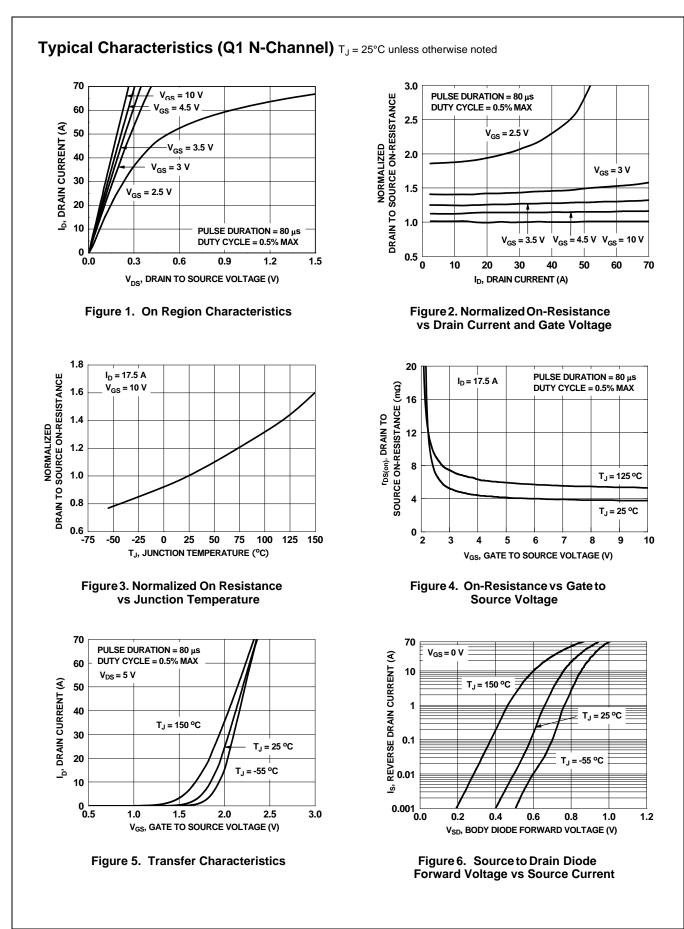
1.R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.

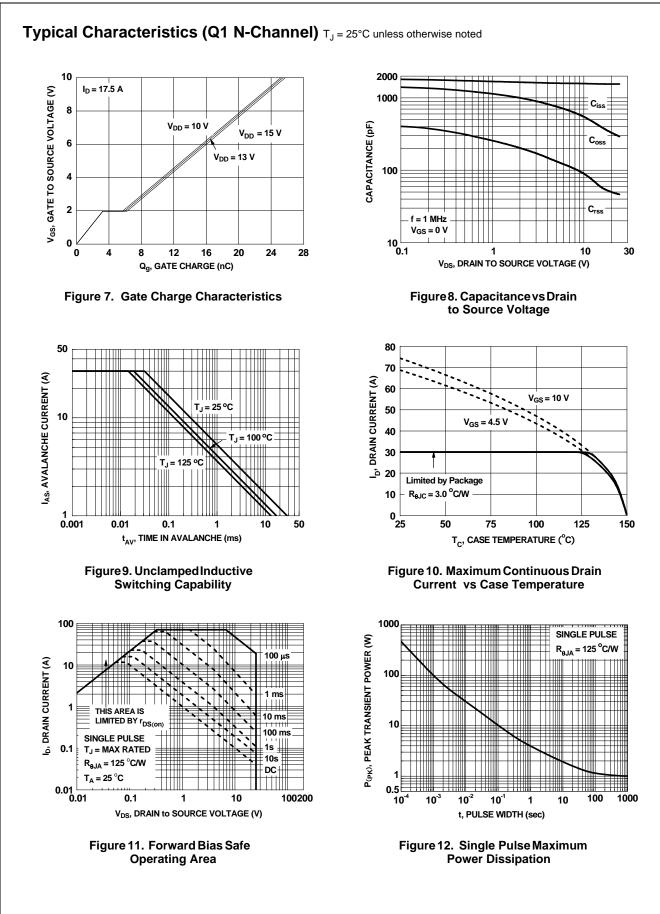


2 Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.

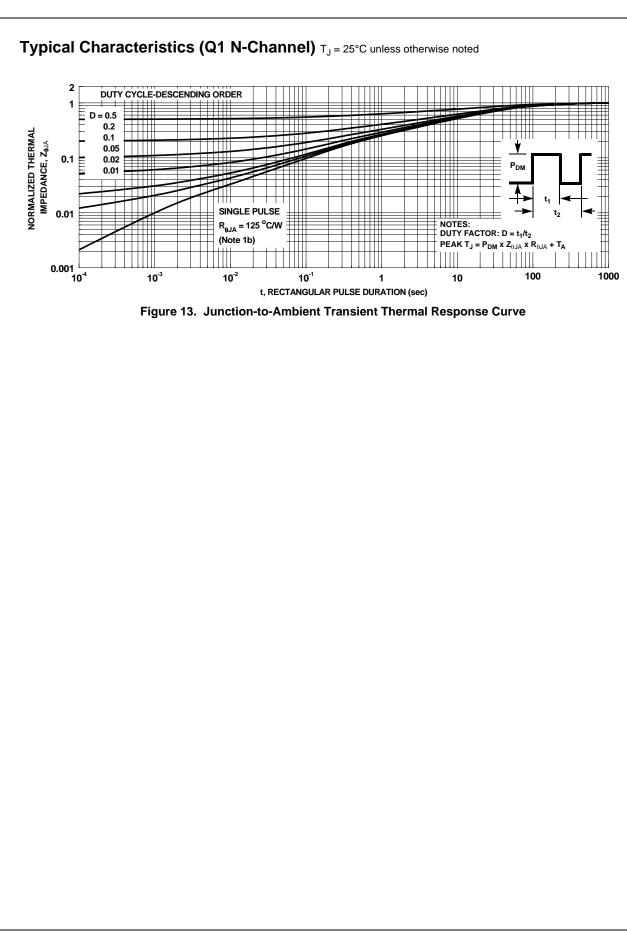
3. Q1 : E_{AS} of 29 mJ is based on starting T_J = 25 $^{\circ}$ C; N-ch: L = 1.2 mH, I_{AS} = 7 A, V_{DD} = 23 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 16 A.

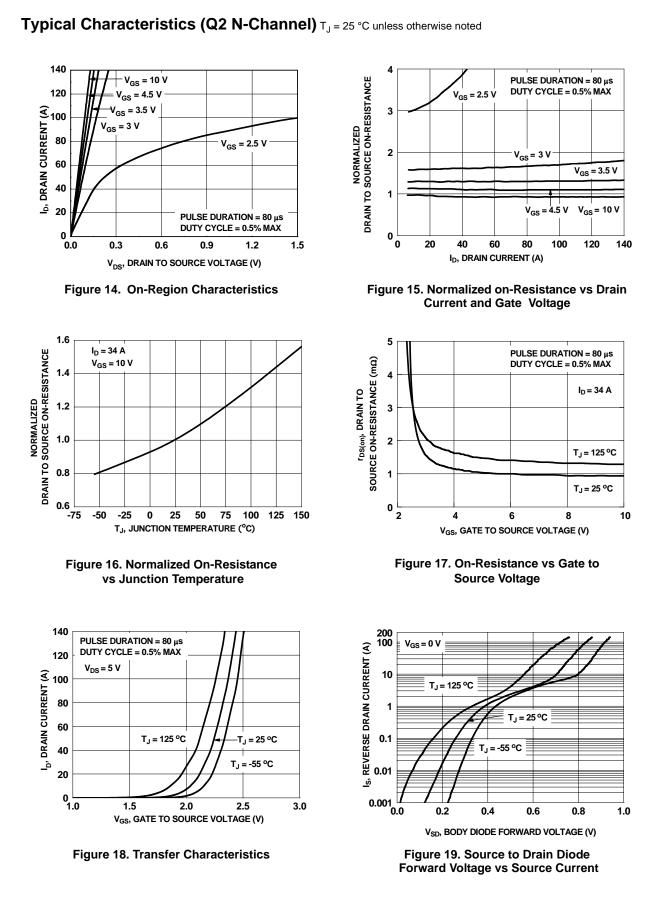
Q2: E_{AS} of 145 mJ is based on starting $T_J = 25$ °C; N-ch: L = 0.9 mH, $I_{AS} = 18$ A, $V_{DD} = 23$ V, $V_{GS} = 10$ V. 100% test at L = 0.1 mH, $I_{AS} = 39$ A. 4. As an N-ch device, the negative Vgs rating is for low duty cycle pulse occurrence only. No continuous rating is implied.

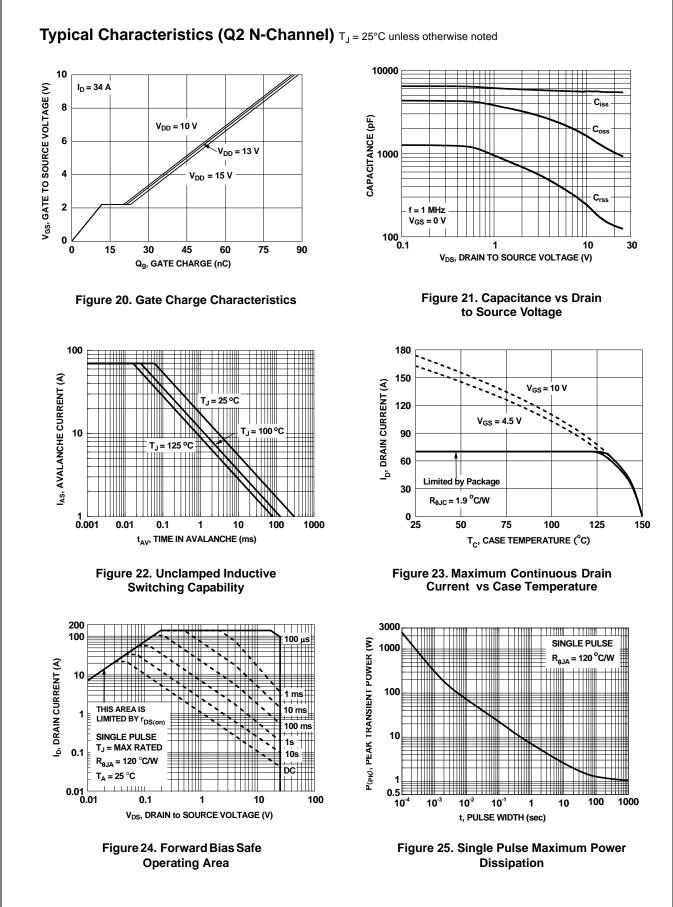


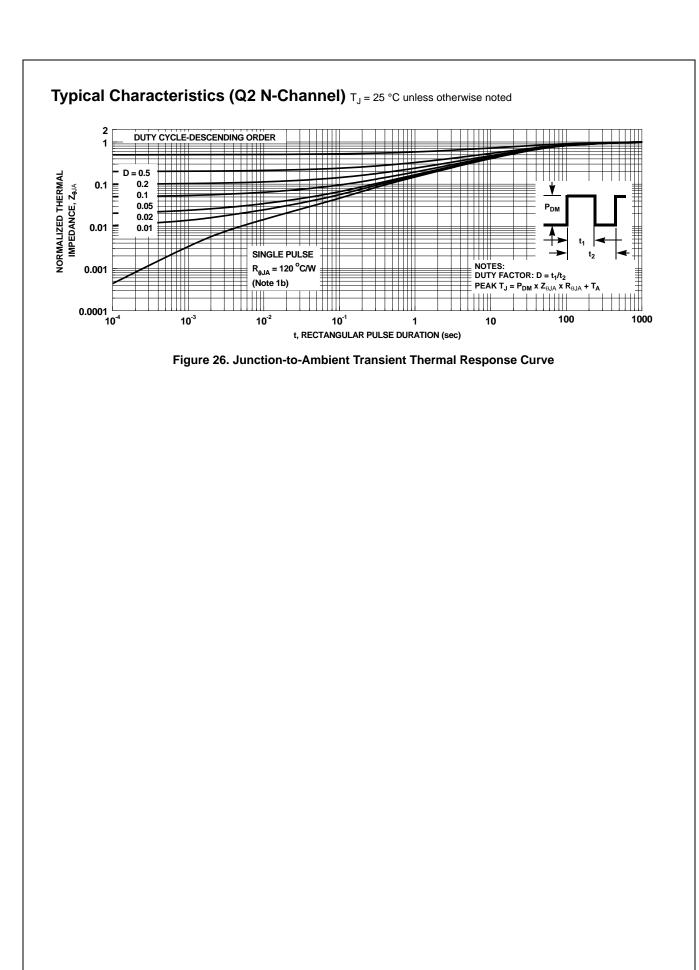












Typical Characteristics (continued)

SyncFET Schottky body diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 27 shows the reverse recovery characteristic of the FDMS3622S.

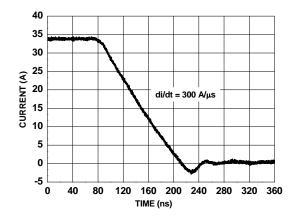


Figure 27. FDMS3622S SyncFET body diode reverse recovery characteristic

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

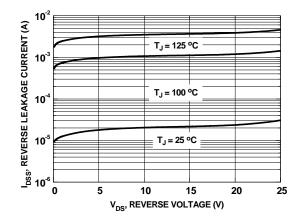
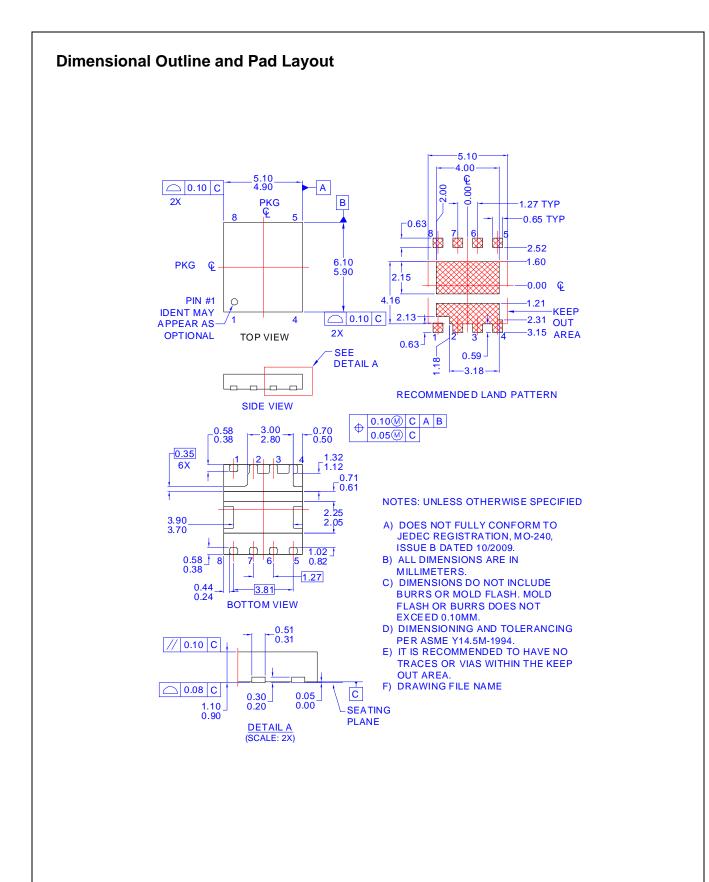


Figure 28. SyncFET body diode reverse leakage versus drain-source voltage

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